

# The effect of indium

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## The effect of indium oxide ( $\text{In}_2\text{O}_3$ ) dopant on the electrical properties of $\text{LiTaO}_3$ thin film-based sensor

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### ABSTRACT

The effect of the indium oxide ( $\text{In}_2\text{O}_3$ ) dopant on the electrical properties of the lithium tantalate ( $\text{LiTaO}_3$ ) thin film-based sensor was investigated in this study.  $\text{LiTaO}_3$  thin film was made on p-type Si (100) substrates by applying the chemical solution deposition (CSD) method. The  $\text{LiTaO}_3$  thin film was annealed at the temperature of  $850^\circ\text{C}$  for 15 h. Surface morphology and elemental characterization analysis were obtained by using SEM-EDX (scanning electron microscopy–energy-dispersive X-ray spectroscopy). Then, the dielectric constant value and the photoresistive characteristic of  $\text{LiTaO}_3$  thin film were measured to determine the effect of the  $\text{In}_2\text{O}_3$  dopant on the electrical properties of the thin film. From the SEM-EDX measurement, it is observed that the surface of the thin film is still non-homogeneous; therefore, the electron flow will be obstructed. Based on the elemental atomic composition analysis, it appears that the Indium atoms have appeared in the  $\text{LiTaO}_3$  thin films doped by  $\text{In}_2\text{O}_3$  2%, 4%, and 6%. From the results of thin film dielectric constant calculation, it can be seen that the dielectric constant value between undoped and  $\text{In}_2\text{O}_3$ -doped  $\text{LiTaO}_3$  thin film does not change, which is 2.44. The photoresistive value shows that the Indium dopant decreases the resistivity but increases the conductivity of the thin film. Based on the photoresistive characteristic measurement results, it can be concluded that the  $\text{LiTaO}_3$  thin film can be used as a light sensor, and  $\text{In}_2\text{O}_3$  dopant can increase the conductivity of the  $\text{LiTaO}_3$  thin film.

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## 1. Introduction

The rapid development of innovative thin film technology is one principle factor in current smart material technology due to its material and cost efficiencies [1–3]. One of the primary goals of modern science and engineering that will have a big impact on technological applications is thin films with electronic semiconductor sensor due to their dielectric constant, dielectric loss, pyroelectric coefficient, and dielectric tunability properties [2,4–6]. Ferroelectric thin films are potentially important materials for electronic and optical electricity. One material that could be used in making a thin film is

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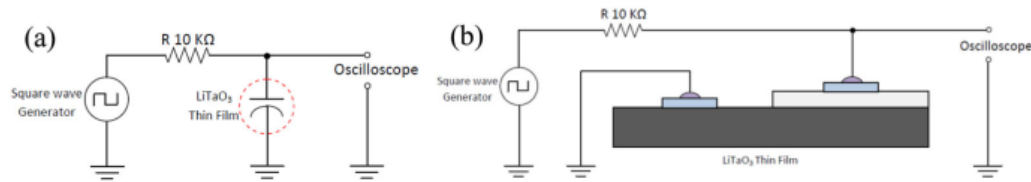


Figure 1. Step response measurement: (a) schematic, (b) circuit connection.

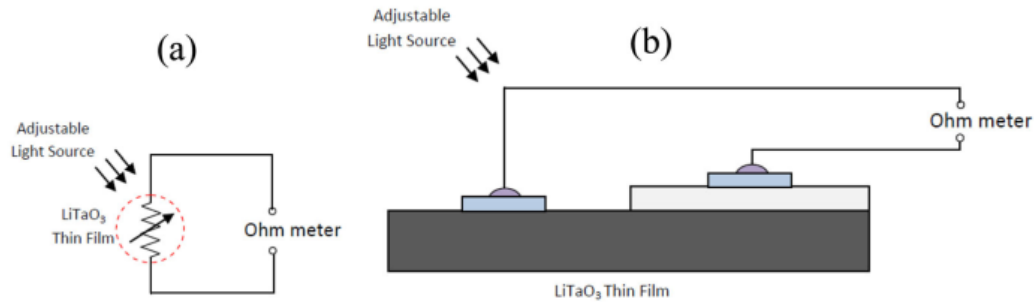
lithium tantalate ( $\text{LiTaO}_3$ ) [5–12]. Materials like barium strontium titanate (BST) have high responsivity toward heat [19] and light or  $\text{NaNO}_2$  [4,13–16].  $\text{LiTaO}_3$  is ferroelectric material having an excellent of pyroelectric, piezoelectric, refractive, electro-optical, and non-linear optical properties.  $\text{LiTaO}_3$  is suitable for applications to non-linear optics, integrated optics, optical coating, lasers, and sensors like light sensors [1,5,9].

In this paper, a thin film [22]  $\text{LiTaO}_3$  was made by adding indium oxide ( $\text{In}_2\text{O}_3$ ) dopant. The substrate used is p-type silicon material (100), using the chemical solution deposition (CSD) method. A CSD method is a method of making thin films by depositing chemical solutions on the substrate, followed by a spin coating technique with a rotating speed of 4000 rpm [9,10,17–20]. Scanning electron microscopy (SEM) is a microscope that uses the principle of electrons emitted on a sample. SEM could [12] be used in evaluating the surface morphology and thickness of the as-deposited films. Energy-dispersive X-ray spectroscopy (EDX) is an analytical technique used to analyze elements or chemical characterization of  $\text{LiTaO}_3$  thin films. The atomic composition contained in the sample was determined by EDX [1,3,21–23].

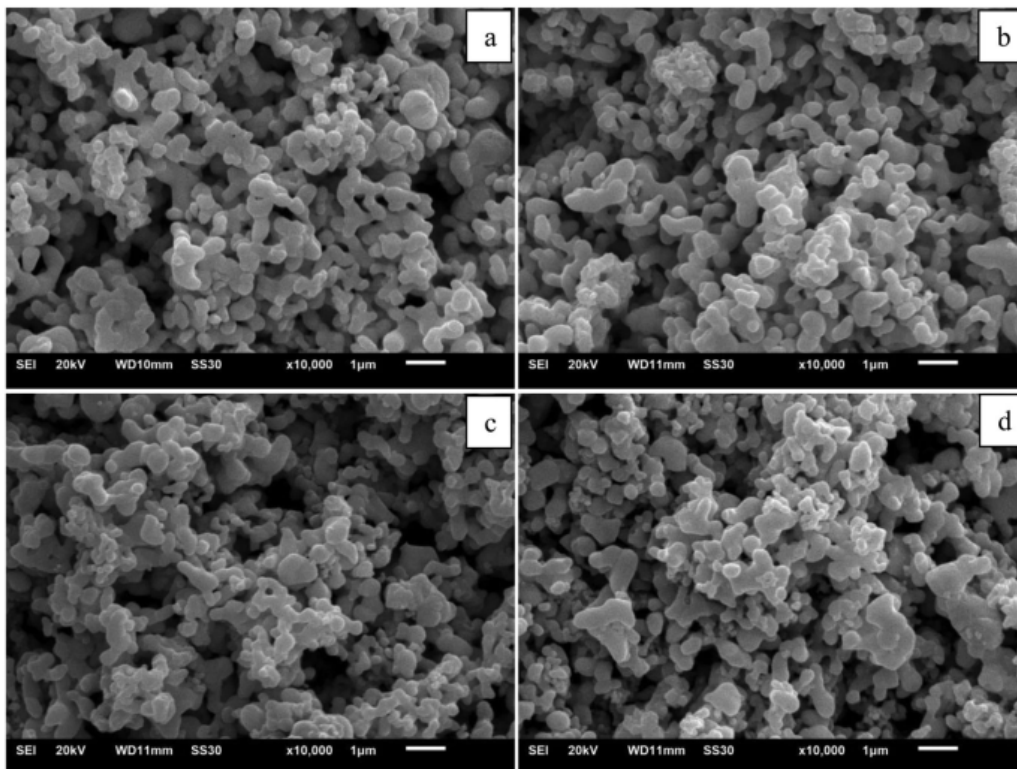
## 2. Experiments

[21] In this [18] search,  $\text{LiTaO}_3$  thin film was grown on a p-type silicon substrate (100). The substrate was cut into a square size of  $1\text{ cm} \times 1\text{ cm}$  using a glass cutter. The substrate was cleaned by dipping in acetone using an ultrasonicator device for 15 min, repeated sequentially with methanol, and deionized [24] water [9,22–27]. The  $\text{LiTaO}_3$  solution was made by reacting [ $(\text{LiTaO}_3)$ , 99.99%], and 2.5 ml of 2-methoxyethanol [ $(\text{CH}_3\text{OCH}_2\text{CH}_2\text{OH})$ ] as the solvent. Then, three types of solutions were produced with doping of 2%, 4%, and 6%  $\text{In}_2\text{O}_3$  (99.99%). The solution was stirred using Vortex 3000. Furthermore, the solution mixture was put inside [13] the ultrasonicator device for 30 min, which produced a homogenous  $\text{LiTaO}_3$  solution. The solution was spin-coated on p-type Si(100) substrates at 4000 rpm speed for 30 s, and it was repeated three times (disposition and rotation) with a 1-min break in between by using CSD method [5–7,9,28]. Then, the annealing process was conducted in a furnace model Nabertherm type B410 for 15 h at  $850^\circ\text{C}$  temperature.

Surface morphology and elemental characterization analysis were obtained by using SEM and EDX. Then, the process of mounting aluminum contacts as a medium in the measurement was conducted. Two aluminum contacts were mounted each on a p-type silicon substrate and [8] thin film layer with a size of  $2\text{ mm} \times 2\text{ mm}$ . Each aluminum contact will be connected to a copper wire using a silver paste. Afterwards, the dielectric [6] constant value and the photoresistive characteristic were measured to determine the effect of the  $\text{In}_2\text{O}_3$  dopant on the electrical properties of the thin film. The dielectric constant of the thin film can be obtained by finding the step response of the thin film.



**Figure 2.** Photoresistive characteristics measurement: (a) schematic, (b) circuit connection.



**Figure 3.** Surface morphology of LiTaO<sub>3</sub> at different doped concentrations: (a) undoped, (b) 2% In<sub>2</sub>O<sub>3</sub> doped, (c) 4% In<sub>2</sub>O<sub>3</sub> doped, (d) 6% In<sub>2</sub>O<sub>3</sub> doped.

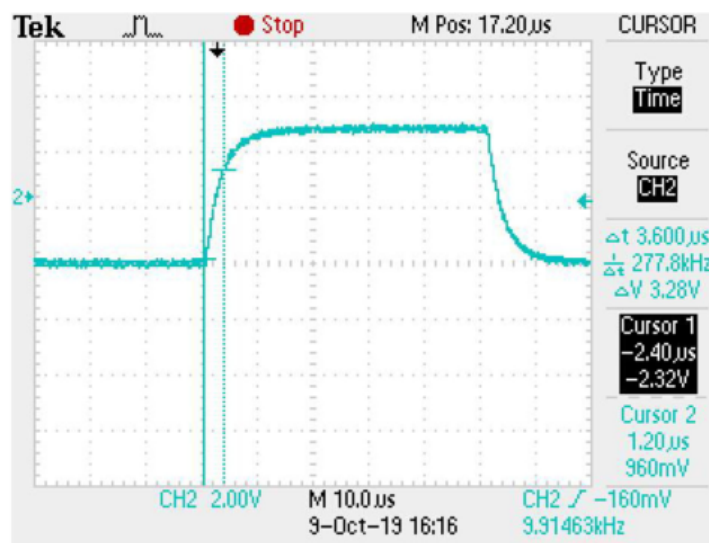
From the step response, we can get the time constant ( $\tau$ ) value of the thin film<sup>9</sup> to calculate the dielectric constant ( $k$ ) of the thin film. We can get the step response of the thin film by connecting the LiTaO<sub>3</sub> thin film in series with resistor and square wave generator. The step response, then, can be measured using an oscilloscope. The circuit schematic and connection of the thin film for the step response measurement carried out in this study are presented in Figure 1.

In order to measure the photoresistive characteristics of the thin film, an adjustable incandescent lamp as the light source was used. Then, the resistance of the thin film was measured by using digital Ohm meter. The circuit schematic and



**Table 1.** Undoped and  $\text{In}_2\text{O}_3$ -doped  $\text{LiTaO}_3$  thin film elemental composition.

$\text{LiTaO}_3$ thin film	Element	keV	Mass%	Error%	Atom%	K
Undoped	O K	0.525	7.12	0.41	46.76	7.0286
	Ta M	1.709	77.65	0.33	45.11	82.8410
	Au M	2.121	15.24	0.59	8.13	10.1304
2% Indium doped	O K	0.525	6.93	0.37	45.82	6.8535
	In L	3.285	1.82	0.37	1.68	1.7481
	Ta M	1.709	72.84	0.29	42.60	78.5727
	Au M	2.121	18.41	0.50	9.90	12.8257
4% Indium doped	O K	0.525	7.49	0.42	47.29	7.2259
	In L	3.285	5.53	0.40	4.87	5.4352
	Ta M	1.709	70.48	0.33	39.37	75.6721
	Au M	2.121	16.50	0.55	8.47	11.6668
6% Indium doped	O K	0.525	9.56	0.40	53.97	9.2236
	In L	3.285	5.08	0.39	4.00	4.9785
	Ta M	1.709	70.73	0.31	35.32	75.5726
	Au M	2.121	14.63	0.53	6.71	10.2253

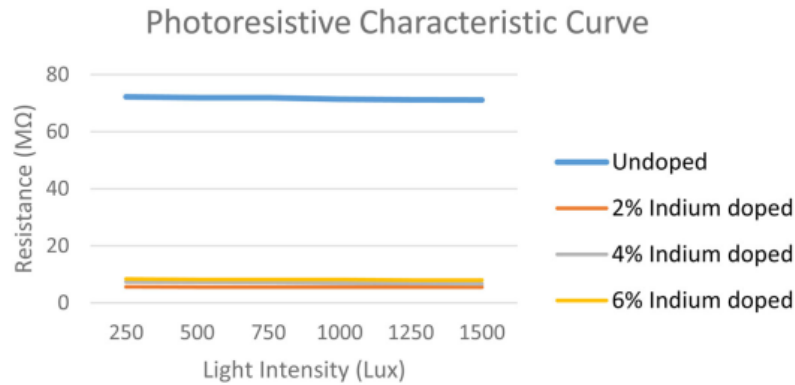
**Figure 4.** Step response of  $\text{LiTaO}_3$  thin film.

connection of the thin film for photoresistive characteristics measurement are shown in Figure 2.

## 16 3. Results and discussion

### 3.1. Surface morphology and elemental characterization analysis

Surface morphology and elemental characterization analysis were obtained by using SEM-EDX. The results of morphology analysis are presented in Figure 3, and elemental characterization measurement is in Table 1. The surface morphology measurement results show that the  $\text{LiTaO}_3$  thin films with and without  $\text{In}_2\text{O}_3$  doping have formed on the silicon substrate. However, the surface of the thin film is still non-homogenous, which causes the flow of electrons in the thin film can be inhibited. Meanwhile, from



**Figure 5.** Photoresistive characteristic of undoped and  $\text{In}_2\text{O}_3$ -doped  $\text{LiTaO}_3$  thin film.

the analysis of the elemental atomic composition, it appears that the Indium atoms have appeared in the  $\text{LiTaO}_3$  thin film doped with  $\text{In}_2\text{O}_3$ . This result shows that the process of adding  $\text{In}_2\text{O}_3$  dopants was done successfully.

### 3.2. Dielectric constant

The step response measurement results show that there is no difference in the value of the time constant ( $\tau$ ) between  $\text{In}_2\text{O}_3$ -doped and undoped  $\text{LiTaO}_3$  film. Measured  $\text{LiTaO}_3$  thin film time constant is  $3.6\mu\text{s}$ . The measurement result of the  $\text{LiTaO}_3$  thin film step response can be seen in Figure 4.

From the measured time constant ( $\tau$ ), the thin film dielectric constant ( $k$ ) can be calculated as follows:

$$\text{Series RC circuit resistance } R = 10 \text{ K}\Omega = 10^4 \Omega;$$

$$\text{Thin film area } A = 0.5 \text{ cm}^2 = 5 \times 10^{-5} \text{ m}^2;$$

$$\text{Thin film thickness } d = 3 \mu\text{m} = 3 \times 10^{-6} \text{ m};$$

$$\text{Permittivity of vacuum } \epsilon_0 = 8.854 \times 10^{-12} \text{ F/m}$$

$$C = \frac{\tau}{R} = \frac{3.6 \times 10^{-6} \text{ s}}{10^4 \Omega} = 3.6 \times 10^{-10} \text{ F}$$

$$k = \frac{Cd}{\epsilon_0 A} = \frac{(3.6 \times 10^{-10} \text{ F})(3 \times 10^{-6} \text{ m})}{(8.854 \times 10^{-12} \text{ F/m})(5 \times 10^{-5} \text{ m}^2)} = 2.44$$

### 3.3. Photoresistive characteristics

The result of the measurement of  $\text{LiTaO}_3$  thin film photoresistive characteristics is shown in Figure 5. The results of the measurement show that the value of the resistance of the thin film decreases when the intensity of light hitting the surface of the thin film increases. Photoresistive characteristics measurement also indicates that  $\text{LiTaO}_3$  thin film without  $\text{In}_2\text{O}_3$  dopant has resistance value higher than  $70 \text{ M}\Omega$ , whereas  $\text{LiTaO}_3$  thin film with  $\text{In}_2\text{O}_3$  dopant has resistance value below  $10 \text{ M}\Omega$ . From the measurement results, it can be concluded that  $\text{LiTaO}_3$  thin film can be used as a light sensor, and the addition of the  $\text{In}_2\text{O}_3$  dopant can reduce the resistivity of the thin film or in other words, can increase the conductivity of the thin film.

## 4. Conclusion

LiTaO<sub>3</sub> thin film grown on the p-type silicon substrate (100) by CSD method with 2%, 4%, and 6% In<sub>2</sub>O<sub>3</sub> doping at 850 °C annealing temperature was successfully made. Based on the results of photoresistive characteristic measurement, it can be concluded that LiTaO<sub>3</sub> thin film can be used as a light sensor, and In<sub>2</sub>O<sub>3</sub> dopant can increase the conductivity of the LiTaO<sub>3</sub> thin film.

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## References

- [1] H. Irzaman *et al.*, Surface morphology properties doped RuO<sub>2</sub> (0, 2, 4, 6%) of thin film LiNbO<sub>3</sub>, *IOP Conf. Ser.* **1282**, 012040 (2019). DOI: [10.1088/1742-6596/1282/1/012040](https://doi.org/10.1088/1742-6596/1282/1/012040).
- [2] H. Irzaman *et al.*, Modified spin coating method for coating and fabricating ferroelectric thin films as sensors and solar cells, *InTech* (2017). DOI: [10.5772/66815](https://doi.org/10.5772/66815).
- [3] R. Grissa *et al.*, XPS and SEM-EDX study of electrolyte nature effect on Li electrode in lithium metal batteries, *ACS Appl. Energy Mater.* **1**, 10, 5694 (2018). DOI: [10.1021/acsam.8b01256](https://doi.org/10.1021/acsam.8b01256).
- [4] B. Harsono *et al.*, Ba<sub>0.5</sub>Sr<sub>0.5</sub>TiO<sub>3</sub> based photodiode application as light sensor for automatic lighting control system, *Integrated Sci-Tech: The Interdisciplinary Research Approach* **1**, 37–43 (2015). UPT. Perpustakaan Universitas Lampung, Indonesia.
- [5] N. Djohan *et al.*, The effect of annealing temperature variation on the optical properties test of LiTaO<sub>3</sub> thin films based on Tauc Plot method for satellite technology, *IOP Conf. Ser. Earth Environ. Sci.* **54** (1), 012093 (2017). DOI: [10.1088/1755-1315/54/1/012093](https://doi.org/10.1088/1755-1315/54/1/012093).
- [6] N. Djohan *et al.*, Classification of undoped and 10% Ga<sub>2</sub>O<sub>3</sub>-doped LiTaO<sub>3</sub> thin films based on electrical conductivity and phase characteristic, *ARPN J. Eng. Appl. Sci.* **12** (12), 3779 (2017).
- [7] R. Estrada *et al.*, The optical band gap of LiTaO<sub>3</sub> and Nb<sub>2</sub>O<sub>5</sub>-doped LiTaO<sub>3</sub> thin films based on Tauc Plot method to be applied on satellite, *IOP Conf. Ser. Earth Environ. Sci.* **54** (1), 012092 (2017). DOI: [10.1088/1755-1315/54/1/012092](https://doi.org/10.1088/1755-1315/54/1/012092).
- [8] R. Estrada *et al.*, Electrical properties test of dielectric constant and impedance characteristic thin films of LiTaO<sub>3</sub> and 10% Ga<sub>2</sub>O<sub>3</sub>-doped LiTaO<sub>3</sub>, *ARPN J. Eng. Appl. Sci.* **12**, 3813 (2017).
- [9] N. Djohan *et al.*, Crystalline structure and optical properties of thin film LiTaO<sub>3</sub>, *IOP Conf. Ser. Earth Environ. Sci.* **284**, 012039 (2019). DOI: [10.1088/1755-1315/284/1/012039](https://doi.org/10.1088/1755-1315/284/1/012039).
- [10] N. Djohan *et al.*, The optical band gap based on K-M function on layer of LiTaO<sub>3</sub> with variation treatment of annealing temperature, presented at the International Conference on Smart Green Technology in Electrical and Information Systems (ICSGTEIS), Bali, Indonesia, 25–27 Oct. 2018.
- [11] F. I. W. Sari *et al.*, Analisis Energy Gap dan Indeks Bias LiTaO<sub>3</sub> Didadah Ga<sub>2</sub>O<sub>3</sub> Berdasarkan Metode Reflektansi, Proseding Seminar Nasional Fisika dan Aplikasinya, Bale Sawala Kampus Universitas Padjadjaran, Jatinangor, Bandung, Indonesia, 21 Nov. 2015.
- [12] G. C. Rundupadang *et al.*, Sifat Optik LiTaO<sub>3</sub> Didadah Ga<sub>2</sub>O<sub>3</sub> Berdasarkan Metode Tauc Plot. Proseding Seminar Nasional Fisika dan Aplikasinya, Bale Sawala Kampus Universitas Padjadjaran, Jatinangor, Bandung, Indonesia, 21 Nov. 2015.
- [13] J. Liman *et al.*, Making photodiode based on Ba<sub>0.5</sub>Sr<sub>0.5</sub>TiO<sub>3</sub> thin film on P-type Si (100) substrate with chemical solution deposition (CSD) method, *The Interdisciplinary Research Approach* **1**, 111–114 (2015). UPT. Perpustakaan Universitas Lampung, Indonesia.



- [14] J. Liman *et al.*, Uji Sifat Optik Film Tipis Ba<sub>0.5</sub>Sr<sub>0.5</sub>TiO<sub>3</sub> Di Atas Substrat Corning Glass 7059, *Proseding Pertemuan Ilmiah XXIX Jateng & DIY*, Yogyakarta, 25 Apr. 2015.
- [15] Y. A. Bonga *et al.*, Analisis Energy Gap dan Indeks Bias Film Tipis Ba<sub>0.5</sub>Sr<sub>0.5</sub>TiO<sub>3</sub> Didadah Ga<sub>2</sub>O<sub>3</sub> Berdasarkan Metode Reflektansi. *Proseding Seminar Nasional Fisika dan Aplikasinya*, Bale Sawala Kampus Universitas Padjadjaran, Jatinangor, Bandung, Indonesia, 21 Nov. 2015.
- [16] A. Parapa *et al.*, Sifat Optik Film Tipis Ba<sub>0.5</sub>Sr<sub>0.5</sub>TiO<sub>3</sub> Didadah Ga<sub>2</sub>O<sub>3</sub> Berdasarkan Metode Tauc Plot. *Proseding Seminar Nasional Fisika dan Aplikasinya*, Bale Sawala Kampus Universitas Padjadjaran, Jatinangor, Bandung, Indonesia, 21 Nov. 2015.
- [17] H. Irzaman *et al.*, Electrical properties of photodiode BST thin film doped with ferrium oxide using chemical deposition solution method, *J. At. Indonesia, Batan* **6** (2), 57 (2010). [in Indonesian].
- [18] H. Irzaman *et al.*, Electrical properties of photodiode Ba<sub>0.25</sub>Sr<sub>0.75</sub>TiO<sub>3</sub> (BST) thin film doped with ferric oxide on p-type Si (100) substrate using chemical solution deposition method, *J. At. Indonesia*. **37** (3), 133 (2011). [in Indonesian]. DOI: [10.17146/ajj.2011.81](https://doi.org/10.17146/ajj.2011.81).
- [19] H. Irzaman *et al.*, The effect of Ba/Sr ratio on electrical and optical properties of Ba<sub>x</sub>Sr<sub>(1-x)</sub>TiO<sub>3</sub> (x = 0.25; 0.35; 0.45; 0.55) thin film semiconductor, *Ferroelectrics* **445** (1), 4 (2013). DOI: [10.1080/00150193.2012.742351](https://doi.org/10.1080/00150193.2012.742351).
- [20] H. Irzaman *et al.*, Test on electrical conductivity and dielectric of lithium tantalite (LiTaO<sub>3</sub>) doped by (Nb<sub>2</sub>O<sub>5</sub>) using chemical deposition method, *Proceedings of National Workshop on Physics*, 2010 pp. 175–183. [in Indonesian].
- [21] J. Liman *et al.*, Making photodiode based on Ba<sub>0.5</sub>Sr<sub>0.5</sub>TiO<sub>3</sub> thin film on P-type Si (100) substrate with chemical solution deposition (CSD) method, *The Interdisciplinary Research Approach* **1**, 111–114 (2015). UPT. Perpustakaan Universitas Lampung, Indonesia.
- [22] C. Zhao *et al.*, A novel photocatalyst, Y<sub>2</sub>SiO<sub>5</sub>:Pr<sup>3+</sup>,Li/Pt-Nanb<sub>x</sub>Ta<sub>1-x</sub>O<sub>3</sub>, for highly efficient photocatalytic hydrogen evolution under visible-light irradiation, *J. Mol. Liq.* **277**, 1 (2019). DOI: [10.1016/j.molliq.2018.12.056](https://doi.org/10.1016/j.molliq.2018.12.056).
- [23] A. Abdel-Ghany *et al.*, Improved electrochemical performance of LiNi<sub>0.5</sub>Mn<sub>0.5</sub>O<sub>2</sub> by Li-enrichment and AlF<sub>3</sub> coating, *Materialia* **5**, 100207 (2019). DOI: [10.1016/j.mtla.2019.100207](https://doi.org/10.1016/j.mtla.2019.100207).
- [24] H. Irzaman *et al.*, Application of lithium tantalate (LiTaO<sub>3</sub>) films as light sensor to monitor the light status in the Arduino Uno base energy-saving automatic light prototype and passive infrared sensor, *Ferroelectrics* **524** (1), 44 (2018). DOI: [10.1080/00150193.2018.1432842](https://doi.org/10.1080/00150193.2018.1432842).
- [25] H. Irzaman *et al.*, Optical and structural properties of lanthanum doped lithium niobate thin films, *Ferroelectrics*, **502** (1), 9–18 (2016). DOI: [10.1080/00150193.2016.1232579](https://doi.org/10.1080/00150193.2016.1232579).
- [26] H. Irzaman *et al.*, Characterization of Ba<sub>0.55</sub>Sr<sub>0.45</sub>TiO<sub>3</sub> films as light and temperature sensors and its implementation on automatic drying system model, *Integrated Ferroelectrics*, **168** (1), 130–150 (2016). DOI: [10.1080/10584587.2016.1159537](https://doi.org/10.1080/10584587.2016.1159537).
- [27] H. Irzaman *et al.*, Development of ferroelectric solar cells of barium strontium titanate (Ba<sub>x</sub>Sr<sub>1-x</sub>TiO<sub>3</sub>) for substituting conventional battery in LAPAN-IPB Satellite (LISAT), *Procedia Environmental Sciences* **33**, 607–614 (2016). DOI: [10.1016/j.proenv.2016.03.114](https://doi.org/10.1016/j.proenv.2016.03.114).
- [28] I. Irzaman *et al.*, Effect of annealing times for LiTaSiO<sub>5</sub> thin films on structure, nano scale gain size and band gap, *J. Mater. Res.* **1**, 7 (2014).

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---

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---

19

Irzaman, Henni Sitompul, Masitoh, Mohammad Misbakhushudur, Mursyidah. "Optical and structural properties of lanthanum doped lithium niobate thin films", Ferroelectrics, 2016

Publication

---

20

Irzaman, Ridwan Siskandar, Nida Nabilah, Aminullah, Brian Yulianto, Kholoud Ahmed Hamam, Husin Alatas. " Application of lithium tantalate (LiTaO ) films as light sensor to monitor the light status in the Arduino Uno based energy-saving automatic light prototype and passive infrared sensor ", Ferroelectrics, 2018

Publication

---

21

Irzaman, Yunus Pebriyanto, Epa Rosidah Apipah, Iman Noor, Ahmad Alkadri. " Characterization of Optical and Structural of Lanthanum Doped LiTaO Thin Films ", Integrated Ferroelectrics, 2015

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